

High quality test pattern generation and boolean satisfiability

Eggersgluß, Stephan, author

Deskripsi Lengkap: <https://lib.ui.ac.id/detail?id=20418663&lokasi=lokal>

Abstrak

This book provides an overview of automatic test pattern generation (ATPG) and introduces novel techniques to complement classical ATPG, based on Boolean Satisfiability (SAT). A fast and highly fault efficient SAT-based ATPG framework is presented which is also able to generate high-quality delay tests such as robust path delay tests, as well as tests with long propagation paths to detect small delay defects.